ABSTRACT OF THE DISCLOSURE

The present invention relates to a test pin unit for a PCB test device capable of applying an electrical signal to each contact point of a PCB in a PCB test device which detects a certain defect in a PCB based on an electrical connection state by applying an electrical signal to each contact point of a PCB and relates to a feeding device capable of feeding the test pin unit to a certain place on a PCB.

The test pin unit for a PCB(Printed Circuit Board) test device according to the present invention includes a body installed in the interior of a PCB test device in such a manner that the body is moved in a vertical direction on a PCB which is a tested object, a moving body which is movable in a horizontal direction with respect to the body and has a sliding surface formed at one end of the same in a vertical direction of the PCB, a first movement control means for controlling a horizontal movement with respect to the body of the moving body, a moving member slidably attached to a sliding surface of the moving body and is slidably moved toward the PCB and contacting the test pin of the end portion with a certain contact point of the PCB for thereby applying an electrical signal through the test pin, and a second movement control means for controlling the sliding movement of the moving member for thereby significantly decreasing the feeding number of the test pin units needed for a PCB test and significantly enhancing a test efficiency of the PCB test device by increasing the number of the test units which are fed at the same time.